



SEMICELL CAL-DIODE

SKCD 47 C 120 I HD

I_F = 85 A

V_{RRM} = 1200 V

Size: 6,86 mm X 6,86 mm

Package: wafer frame

Features

- 600V, 1200V and 1700V
- optimized for high current density
- easy paralleling due to a small forward voltage spread
- positive temperature coefficient
- very soft recovery behavior
- small switching losses
- high ruggedness
- compatible to thick wire bonding
- compatible to all standard solder processes

Typical Applications

- freewheeling diode for IGBT
- optimal at frequencies < 8 kHz

Absolute Maximum Ratings

Symbol	Conditions	Values	Units
V _{RRM}	T _{vj} = 25 °C, I _R = 0,2 mA	1200	V
I _{F(AV)}	T _h = 80 °C, T _{vjmax} = 150 °C	50	A
I _{FSM}	T _{vj} = 25 °C, 10 ms, half sine wave	790	A
	T _{vjmax} = 150 °C, 10 ms, half sine wave	640	A
T _{vjmax}		+ 150	°C

Electrical Characteristics

Symbol	Conditions	min.	typ.	max.	Units
I ² t	T _{vjmax} , 10 ms, half sine wave		2050		A ² s
I _R	T _{vj} = 25 °C, V _{RRM}			0,2	mA
	T _{vj} = 125 °C, V _{RRM}			mA	
V _F	T _{vj} = 25 °C, I _F = 70 A	1,5	1,77		V
	T _{vj} = 125 °C, I _F = 70 A	1,5	1,77		V
V _(TO)	T _{vj} = 125 °C	0,92			V
r _T	T _{vj} = 125 °C	8,3			mΩ

Dynamic Characteristics

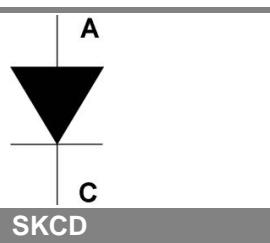
Symbol	Conditions	min.	typ.	max.	Units
t _{rr}	T _{vj} = 25 °C, 50 A, 600 V, 800 A/μs				ns
	T _{vj} = 125 °C, 50 A, 600 V, 800 A/μs				ns
Q _{rr}	T _{vj} = 25 °C, 50 A, 600 V, 800 A/μs		12		μC
	T _{vj} = 125 °C, 50 A, 600 V, 800 A/μs				μC
I _{rrm}	T _{vj} = 25 °C, 50 A, 600 V, 800 A/μs				A
	T _{vj} = 125 °C, 50 A, 600 V, 800 A/μs		43		A

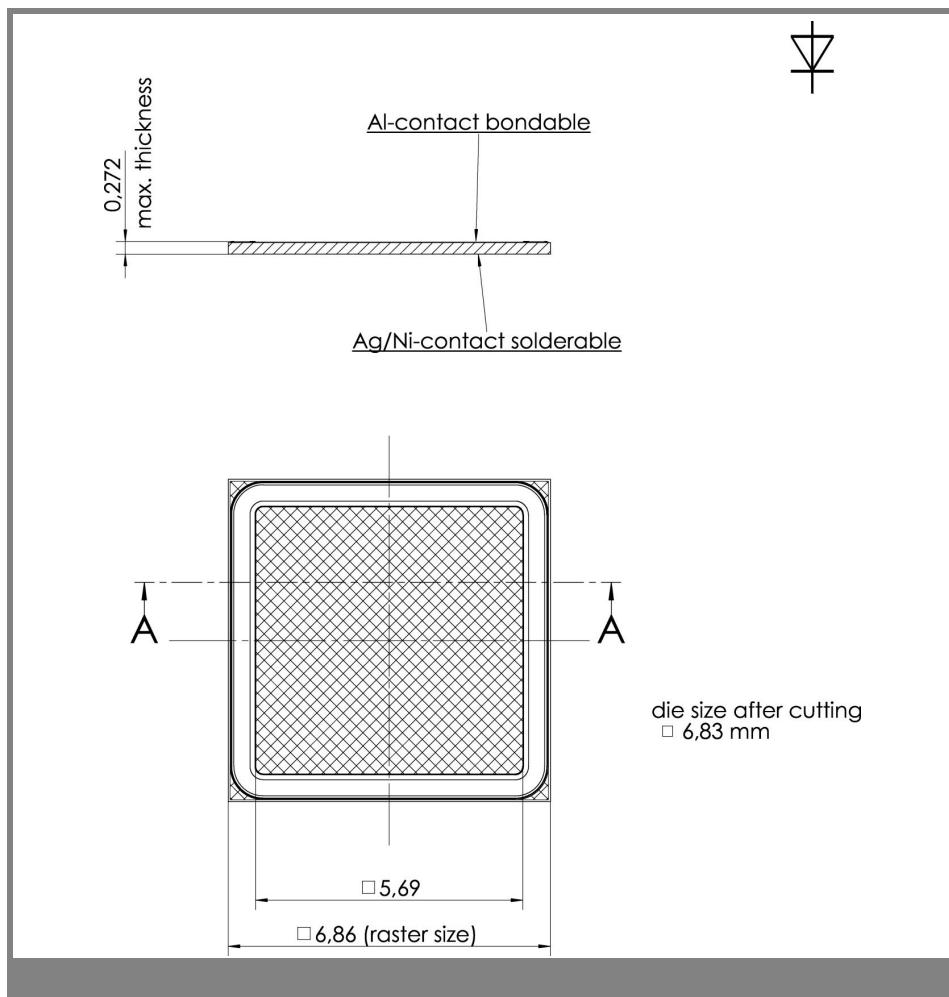
Thermal Characteristics

Symbol	Conditions	min.	typ.	max.	Units
T _{vj}		- 40		+ 150	°C
T _{stg}		- 40		+ 150	°C
T _{solder}	10 min			+ 250	°C
T _{solder}	5 min			+ 320	°C
R _{th(j-h)}	soldered on 0,38 mm DCB, reference point on copper heatsink close to the chip.	0,7			K / W

Mechanical Characteristics

Parameter		Units
raster size	6,86 x 6,86	mm
Area total	47,06	mm ²
Chips / wafer	208	pcs
Anode metallisation	bondable (Al)	
Cathode metallisation	solderable (Ag / Ni)	
wire bond	Al, diameter ≤ 500 μm	





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